

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	42287	fabricat\$4 and (product\$1 or wafer\$1 or chip\$1) with (cost\$3 or pric\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/04 12:10
S2	1996	fabricat\$4 and (product\$1 or wafer\$1 or chip\$1) with (cost\$3 or pric\$3) and critical same dimension\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/04 12:10
S3	1765	fabricat\$4 and (product\$1 or wafer\$1 or chip\$1) with (cost\$3 or pric\$3) and critical same dimension\$1 and (gate\$1 or length\$1 or width\$1 or extention\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/04 12:11
S4	44	fabricat\$4 and (product\$1 or wafer\$1 or chip\$1) with pric\$3 and critical same dimension\$1 and (gate\$1 or length\$1 or width\$1 or extention\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/04 12:13
S5	44	fabricat\$4 and pric\$3 with (product\$1 or wafer\$1 or chip\$1) and critical same dimension\$1 and (gate\$1 or length\$1 or width\$1 or extention\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/04 12:14
S6	6	fabricat\$4 and pric\$3 with (product\$1 or wafer\$1 or chip\$1) same critical same dimension\$1 and (gate\$1 or length\$1 or width\$1 or extention\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/04 12:16
S7	31	fabricat\$4 and pric\$3 with (product\$1 or wafer\$1 or chip\$1) and critical with dimension\$1 and (gate\$1 or length\$1 or width\$1 or extention\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/04 12:17
S8	1749	fabricat\$4 and (pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3) with (product\$1 or wafer\$1 or chip\$1) and critical with dimension\$1 and (gate\$1 or length\$1 or width\$1 or extention\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/04 12:18
S9	130	fabricat\$4 and (pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3) adj (product\$1 or wafer\$1 or chip\$1) and critical with dimension\$1 and (gate\$1 or length\$1 or width\$1 or extention\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/11 12:40

S10	190	fabricat\$4 and (pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3) adj (product\$1 or wafer\$1 or chip\$1 or semiconductor\$1) and critical with dimension\$1 and (gate\$1 or length\$1 or width\$1 or extention\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/04 12:28
S11	18	fabricat\$4 and (pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3) adj (product\$1 or wafer\$1 or chip\$1 or semiconductor\$1) same critical with dimension\$1 and (gate\$1 or length\$1 or width\$1 or extention\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/04 12:22
S12	0	fabricat\$4 and (pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3) adj (product\$1 or wafer\$1 or chip\$1 or semiconductor\$1) and critical with dimension\$1 and (gate\$1 or length\$1 or width\$1 or extention\$1) and aggression	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/04 12:28
S13	56	fabricat\$4 and (pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3) adj (product\$1 or wafer\$1 or chip\$1 or semiconductor\$1) and critical with dimension\$1 and (gate\$1 or length\$1 or width\$1 or extention\$1) and analy\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/04 12:28
S14	1	fabricat\$4 and (pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3) adj (product\$1 or wafer\$1 or chip\$1 or semiconductor\$1) and critical with dimension\$1 and (gate\$1 or length\$1 or width\$1 or extention\$1) and analy\$3 same historical	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/04 12:29
S15	1	(pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3) adj (product\$1 or wafer\$1 or chip\$1 or semiconductor\$1) and critical with dimension\$1 and (gate\$1 or length\$1 or width\$1 or extention\$1) and analy\$3 same historical	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/04 12:29

S16	1	(forecast\$3 or predict\$4) same (pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3 and calculat\$4) adj (product\$1 or wafer\$1 or chip\$1 or semiconductor\$1) and critical with dimension\$1 and (gate\$1 or length\$1 or width\$1 or extention\$1) and analy\$3 same historical	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/04 12:30
S17	4	(forecast\$3 or predict\$4) same (pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3 and calculat\$4) adj (product\$1 or wafer\$1 or chip\$1 or semiconductor\$1) and critical with dimension\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/04 12:34
S18	50	(forecast\$3 or predict\$4) same (pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3 and calculat\$4) with (product\$1 or wafer\$1 or chip\$1 or semiconductor\$1) and critical with dimension\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/04 12:39
S19	3	historical with critical with dimension\$1 with database\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/04 12:42
S20	18	pricing same semiconductor same product\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/04 13:05
S21	185	(fabricat\$4 or manufactur\$3) and (pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3) adj (product\$1 or wafer\$1 or chip\$1) and critical with dimension\$1 and (gate\$1 or length\$1 or width\$1 or extention\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/11 12:41
S22	149	(fabricat\$4 or manufactur\$3) and (pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3) adj (product\$1 or wafer\$1 or chip\$1) and critical adj dimension\$1 and (gate\$1 or length\$1 or width\$1 or extention\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/11 12:41

S23	6277	(fabricat\$4 or manufactur\$3) and (pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3) and critical adj dimension\$1 and (gate\$1 or length\$1 or width\$1 or extention\$1 or size adj reduc\$5)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/11 12:42
S24	1743	(fabricat\$4 or manufactur\$3) and (pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3) and critical adj dimension\$1 with (gate\$1 or length\$1 or width\$1 or extention\$1 or size adj reduc\$5)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/11 12:43
S25	3	(fabricat\$4 or manufactur\$3) and (pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3) and critical adj dimension\$1 with regression same analy\$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/11 12:49
S26	5	"6268226" and gate	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/11 12:46
S27	108	(fabricat\$4 or manufactur\$3) and (pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3) with regression same analy\$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/11 12:50
S28	21	(fabricat\$4 or manufactur\$3) and (pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3) with regression same analy\$5 and (chip\$1 or wafer\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/11 12:53
S29	17	(fabricat\$4 or manufactur\$3) and (pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3) with regression same analy\$5 and semiconductor\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/11 12:55
S30	16	(fabricat\$4 or manufactur\$3) and (estimat\$4 or predict\$4 pr forecast\$4) with (pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3) with regression with analy\$5 and (semiconductor\$1 or chip\$1 or wafer\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/11 12:56
S31	16	(fabricat\$4 or manufactur\$3) and (estimat\$4 or predict\$4 pr forecast\$4) with (pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3) with regression adj analy\$5 and (semiconductor\$1 or chip\$1 or wafer\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/11 12:57

S32	6	(estimat\$4 or predict\$4 or forecast\$4) with (fabricat\$4 or manufactur\$3) same (pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3) with regression adj analy\$5 and (semiconductor\$1 or chip\$1 or wafer\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/11 12:58
S33	7	(estimat\$4 or predict\$4 or forecast\$4) with (fabricat\$4 or manufactur\$3) same (pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3) same regression adj analy\$5 and (semiconductor\$1 or chip\$1 or wafer\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/11 12:59
S34	286015	(estimat\$4 or predict\$4 or forecast\$4) adj (fabricat\$4 or manufactur\$3) same (pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3) sand regression adj analy\$5 and (semiconductor\$1 or chip\$1 or wafer\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/11 12:59
S35	0	(estimat\$4 or predict\$4 or forecast\$4) adj (fabricat\$4 or manufactur\$3) same (pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3) and regression adj analy\$5 and (semiconductor\$1 or chip\$1 or wafer\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/11 12:59
S36	4	(estimat\$4 or predict\$4 or forecast\$4) adj (fabricat\$4 or manufactur\$3) same (pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3) and regression adj analy\$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/11 13:00
S37	2	(estimat\$4 or predict\$4 or forecast\$4) adj (fabricat\$4 or manufactur\$3) same (pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3) and regression adj analy\$5 same historical	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/11 13:01
S38	2	(estimat\$4 or predict\$4 or forecast\$4) adj (fabricat\$4 or manufactur\$3) same (pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3) and regression adj analy\$5 same historical	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/11 13:02
S39	3	(estimat\$4 or predict\$4 or forecast\$4) adj (fabricat\$4 or manufactur\$3) same (pric\$3 or fee or fees or charg\$3 or cost\$3 or market\$3) and regression same analy\$5 same historical	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/11 13:03

S40	1	"6775647" and analysis and historical	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/11 13:04
S41	1	"6775647" and regression and historical	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2005/11/11 13:04